

Description

The VSM70P04 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. This device is well suited for high current load applications.

General Features

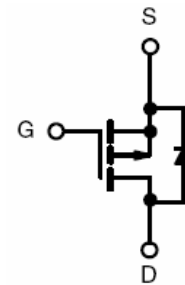
- $V_{DS} = -40V, I_D = -70A$
 $R_{DS(ON)} < 10m\Omega @ V_{GS} = -10V$
- High density cell design for ultra low R_{dson}
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

- Power switch
- Load switch in high current applications
- DC/DC converters



TO-252



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM70P04-T2	VSM70P04	TO-252	330mm	-	2500PCS

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	-40	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	-70	A
Drain Current-Continuous($T_C=100^\circ C$)	$I_D(100^\circ C)$	-49.5	A
Pulsed Drain Current	I_{DM}	-200	A
Maximum Power Dissipation	P_D	130	W
Derating factor		1.04	W/ $^\circ C$
Single pulse avalanche energy ^(Note 5)	E_{AS}	1012	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 150	$^\circ C$

Thermal Characteristic

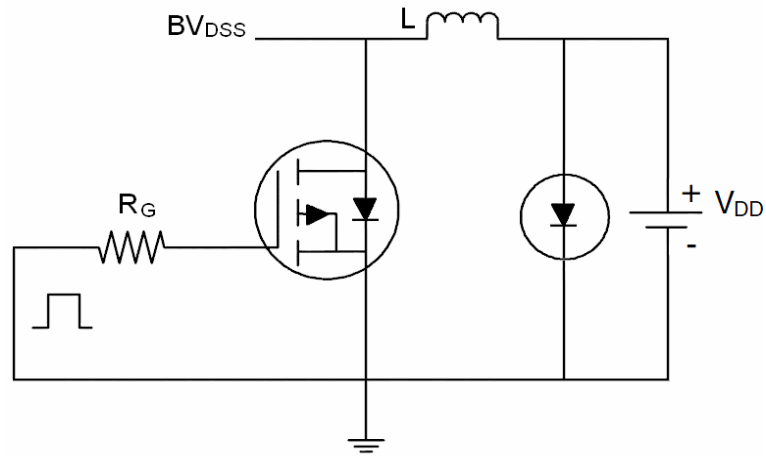
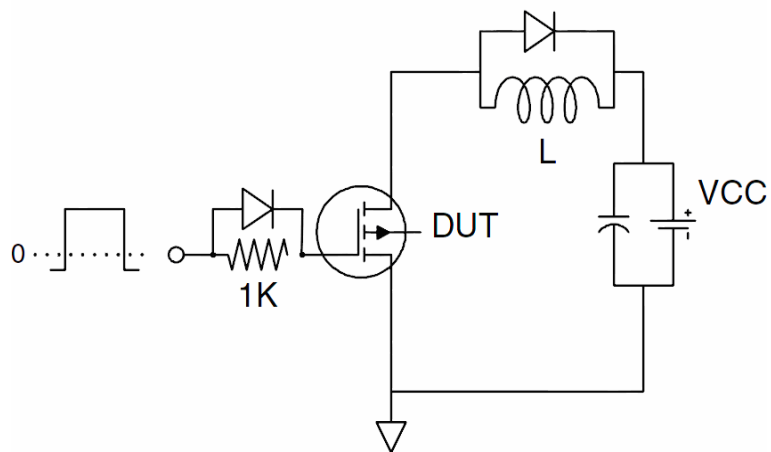
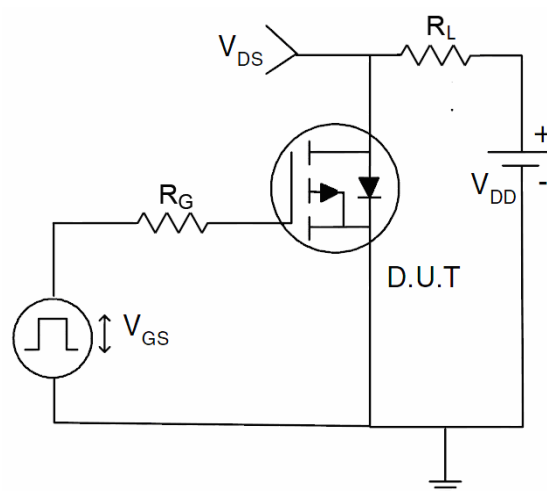
Thermal Resistance, Junction-to-Case ^(Note 2)	$R_{\theta JC}$	0.96	$^\circ C/W$
--	-----------------	------	--------------

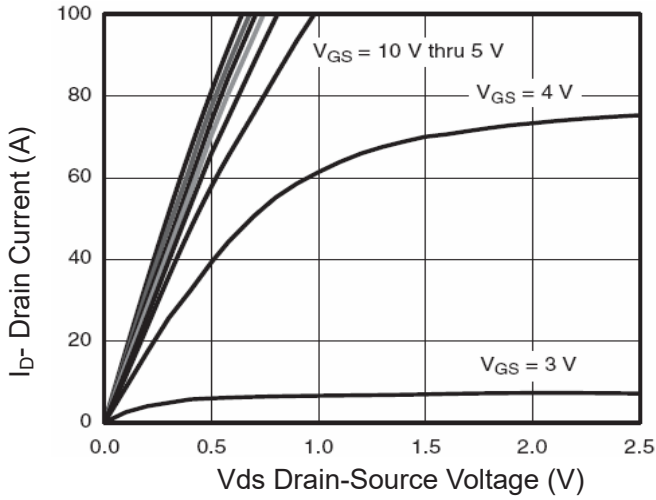
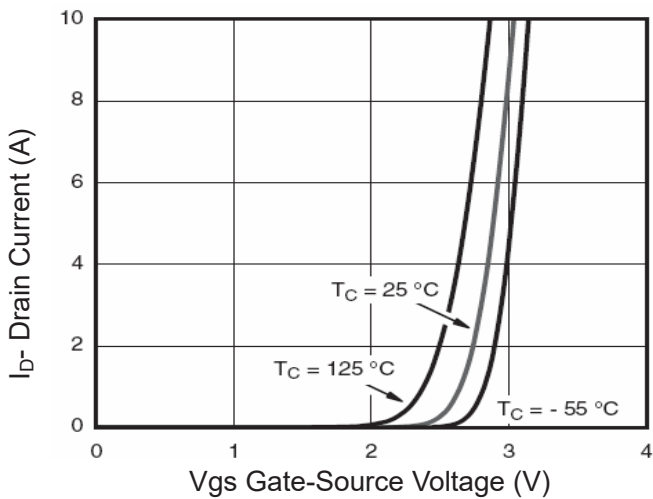
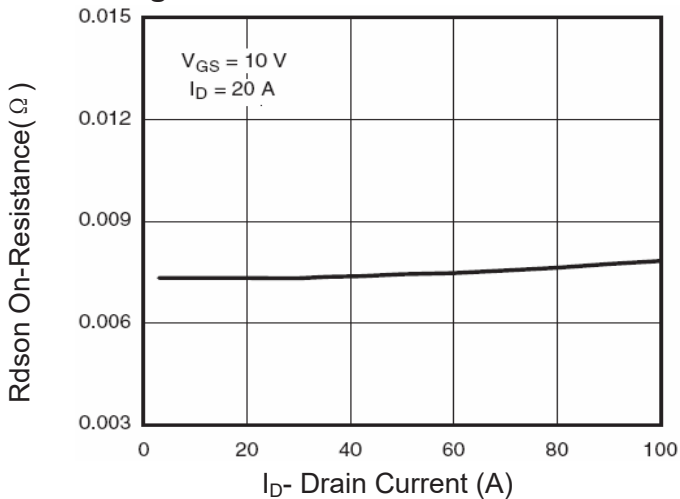
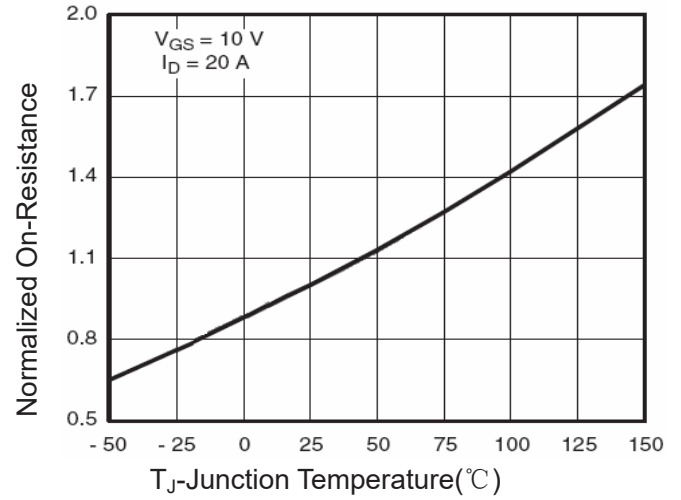
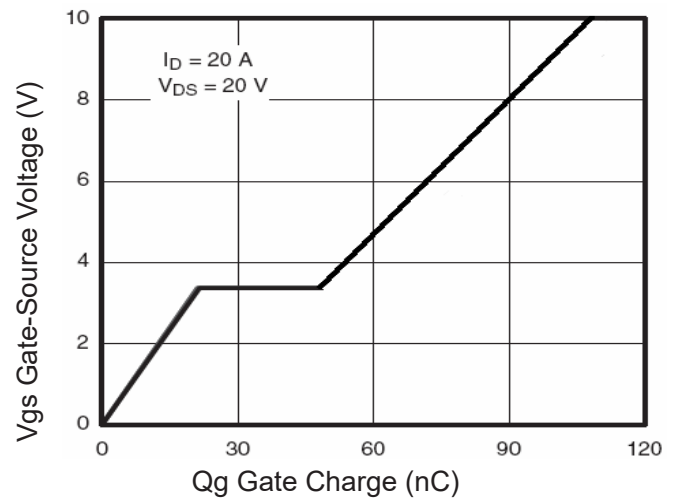
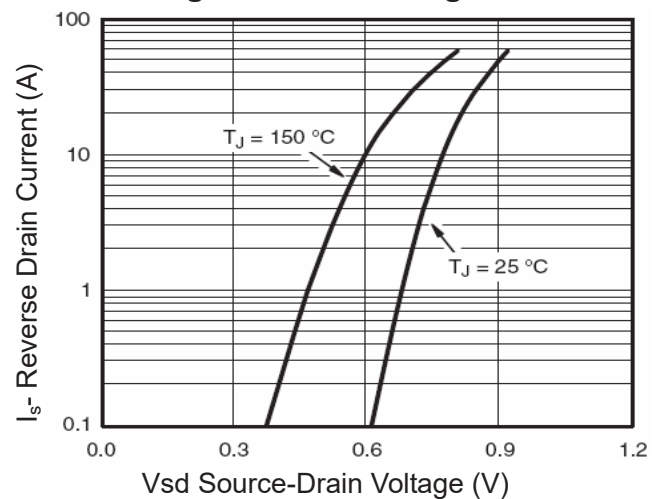
Electrical Characteristics (T_C=25°C unless otherwise noted)

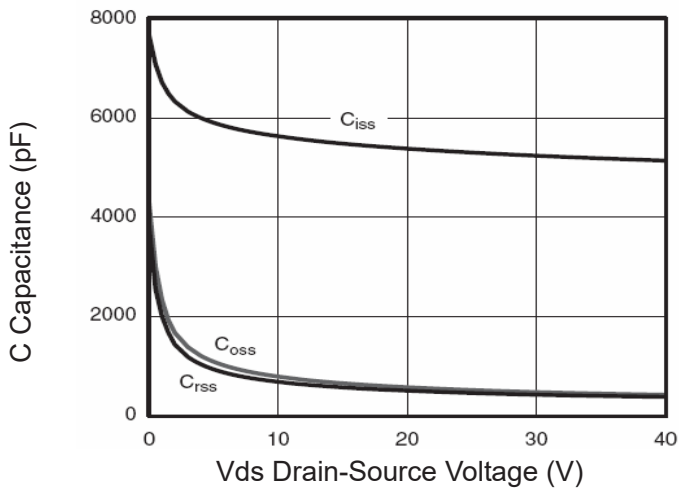
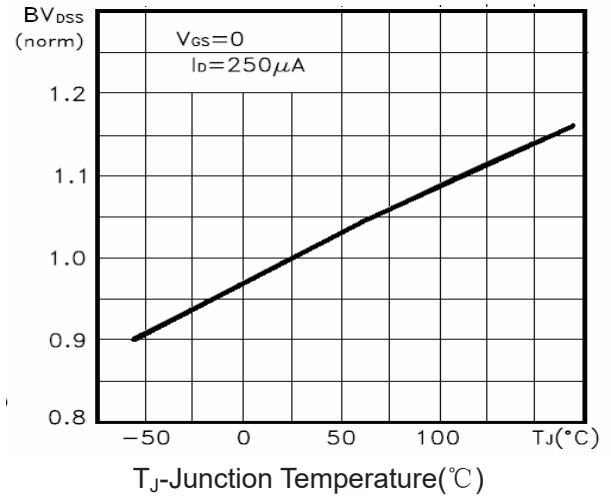
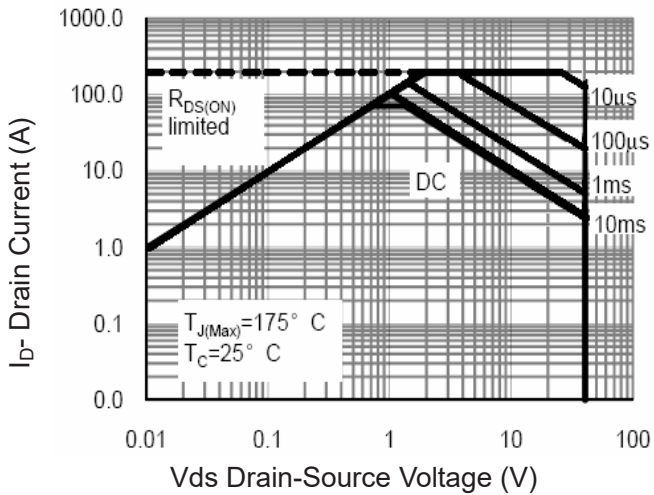
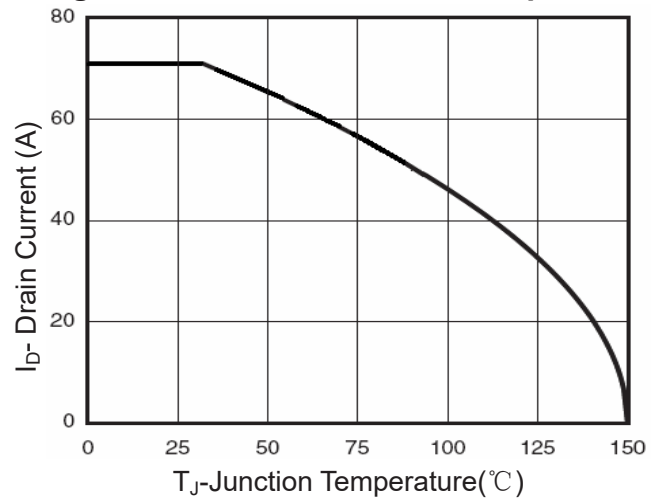
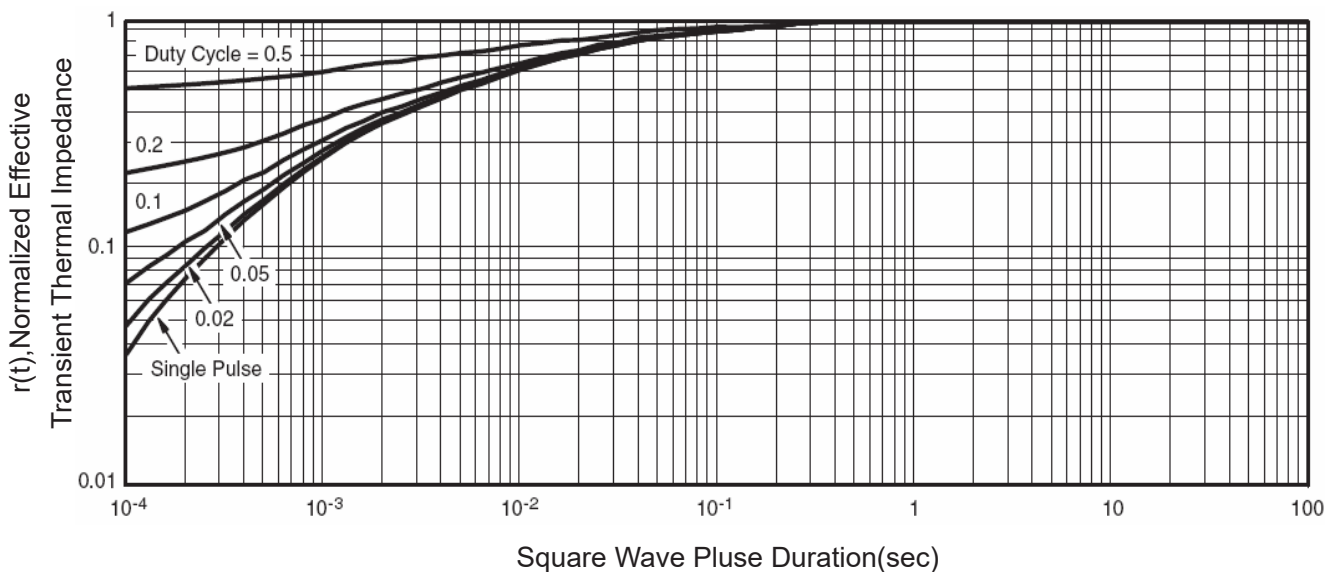
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =-250μA	-40	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-40V, V _{GS} =0V	-	-	-1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =-250μA	-1.2	-1.9	-2.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =-10V, I _D =-20A	-	7.5	10	mΩ
Forward Transconductance	g _{FS}	V _{DS} =-10V, I _D =-20A	-	50	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C _{iss}	V _{DS} =-20V, V _{GS} =0V, F=1.0MHz	-	5380	-	PF
Output Capacitance	C _{oss}		-	570	-	PF
Reverse Transfer Capacitance	C _{rss}		-	500	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}	V _{DD} =-20V, R _L =2Ω, V _{GS} =-10V, R _G =1Ω	-	15	-	nS
Turn-on Rise Time	t _r		-	12	-	nS
Turn-Off Delay Time	t _{d(off)}		-	70	-	nS
Turn-Off Fall Time	t _f		-	18	-	nS
Total Gate Charge	Q _g	V _{DS} =-20, I _D =-20A, V _{GS} =-10V	-	106		nC
Gate-Source Charge	Q _{gs}		-	22		nC
Gate-Drain Charge	Q _{gd}		-	27		nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V, I _S =-70A	-		-1.2	V
Diode Forward Current (Note 2)	I _S		-	-	-70	A
Reverse Recovery Time	t _{rr}	T _J = 25°C, I _F = -70A di/dt = -100A/μs (Note3)	-	53		nS
Reverse Recovery Charge	Q _{rr}		-	50		nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, t ≤ 10 sec.
3. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.
4. Guaranteed by design, not subject to production
5. E_{AS} condition: T_J=25°C, V_{DD}=-20V, V_G=-10V, L=1mH, R_G=25Ω, I_{AS}=45A

Test Circuit
1) E_{AS} Test Circuit

2) Gate Charge Test Circuit

3) Switch Time Test Circuit


Typical Electrical and Thermal Characteristics (Curves)

Figure 1 Output Characteristics

Figure 2 Transfer Characteristics

Figure 3 Rdson- Drain Current

Figure 4 Rdson-Junction Temperature

Figure 5 Gate Charge

Figure 6 Source- Drain Diode Forward


Figure 7 Capacitance vs Vds

Figure 9 BV_{DSS} vs Junction Temperature

Figure 8 Safe Operation Area

Figure 10 I_D Current Derating vs Junction Temperature

Figure 11 Normalized Maximum Transient Thermal Impedance